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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
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Sheet

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of

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Complete if Known

Application Number	New Divisional Application
Filing Date	June 26, 2003
First Named Inventor	Shunpei YAMAZAKI et al.
Art Unit	2815
Examiner Name	G. Eckert, II

Attorney Docket Number

740756-2626

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY		
		US-5,182,620	01/1993	Shimada et al.	
		US-5,739,549	04/1998	Takemura et al.	
		US-5,942,310	08/1999	Moon	
		US-6,067,132	05/2000	Kim	
		US-6,137,551	10/2000	Jeong	
		US-6,271,818	08/2001	Yamazaki et al.	
		US-6,490,014	12/2002	Ohtani et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	Foreign Patent Document		Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ⁴ Number ⁵	Kind Code ² (if known)			
Dle		GB 2-307 326		05/1997	Shin et al.	

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
Dle		Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758.	

Examiner Signature *Dle* Date Considered *4/2004*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI et al.

Filing Date: June 26, 2003 Group: 2815

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
	5,643,826	07/01/1997	Ohtani et al.			
	5,923,962	07/13/1999	Ohtani et al.			
	5,895,933	04/20/1999	Zhang et al.			
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	09-312260	12/02/1997	Japan			Abstract
	10-056184	02/24/1998	Japan			Abstract
	10-247735	09/14/1998	Japan			Abstract
	07-130974	05/19/1995	Japan			Abstract
	07-135323	05/23/1995	Japan			Abstract
	07-169974	07/04/1995	Japan			Abstract
	07-169975	07/04/1995	Japan			Abstract
	07-218932	08/18/1995	Japan			Abstract

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